

Search Notes**Application/Control No.**

10/694,910

Examiner

YUN HAENG LEE

**Applicant(s)/Patent under
Reexamination**

VYSHEDSKIY ET AL.

Art Unit

3766

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IDS	4/11/2008	YHL